

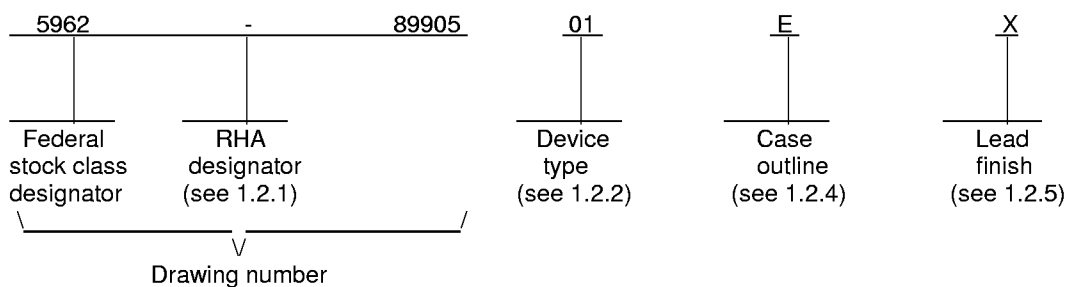
REVISIONS																			
LTR	DESCRIPTION										DATE (YR-MO-DA)				APPROVED				
A	Add device types 02 and 03. Technical and editorial changes throughout.										95-10-06				M. A. Frye				
B	Correct Figure 1 in regard to device types 02 and 03 for case outline 2. Change V_{CC} to V_S in Figure 2. Technical and editorial changes throughout. -lgt										98-03-27				R. Monnin				
C	Add class V for vendor CAGE 48726. Add table IIB. -rrp										99-11-04				R. Monnin				
REV																			
SHEET																			
REV	C	C	C																
SHEET	15	16	17																
REV STATUS OF SHEETS				REV		C	C	C	C	C	C	C	C	C	C	C	C	C	C
				SHEET		1	2	3	4	5	6	7	8	9	10	11	12	13	14
PMIC N/A				PREPARED BY Joseph A. Kerby						DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216									
STANDARD MICROCIRCUIT DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A				CHECKED BY Charles E. Besore															
				APPROVED BY Michael A. Frye															
				DRAWING APPROVAL DATE 91-01-31															
				REVISION LEVEL C						SIZE A	CAGE CODE 67268		5962-89905						
						SHEET 1 OF 17													

1. SCOPE

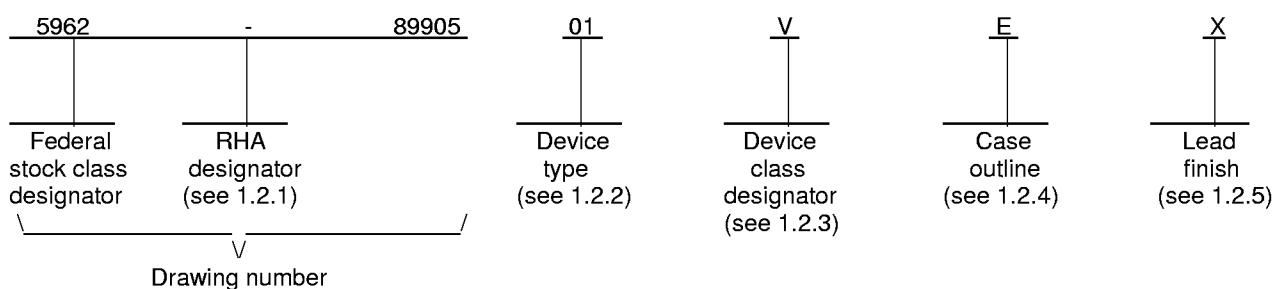
1.1 Scope. This drawing documents two product assurance class levels consisting of high reliability (device classes Q and M) and space application (device class V). A choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of Radiation Hardness Assurance (RHA) levels are reflected in the PIN.

1.2 PIN. The PIN is as shown in the following examples.

For device classes M and Q:



For device class V:



1.2.1 RHA designator. Device classes Q and V RHA marked devices meet the MIL-PRF-38535 specified RHA levels and are marked with the appropriate RHA designator. Device class M RHA marked devices meet the MIL-PRF-38535, appendix A specified RHA levels and are marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) identify the circuit function as follows:

Device type	Generic number	Circuit function
01	1823	High speed PWM controller
02	1823A	High speed PWM controller
03	1823B	High speed PWM controller

1.2.3 Device class designator. The device class designator is a single letter identifying the product assurance level as listed below. Since the device class designator has been added after the original issuance of this drawing, device classes M and Q designators will not be included in the PIN and will not be marked on the device.

Device class	Device requirements documentation
M	Vendor self-certification to the requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A
Q or V	Certification and qualification to MIL-PRF-38535

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 2

1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line
2	CQCC1-N20	20	Square leadless chip carrier

1.2.5 Lead finish. The lead finish is as specified in MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

1.3 Absolute maximum ratings. 1/

Supply voltage (V_S) :	
Device type 01	30 V dc
Device types 02 and 03	22 V dc
DC output current, source or sink	0.5 A
Pulse output current, sink or source (0.5 μ s)	
Device type 01	2.0 A
Device types 02 and 03	2.2 A
Analog input voltage :	
Device type 01 (pins 1, 2, 7, 8, and 9) 1/	-0.3 V dc to 6.0 V dc
Device types 02 and 03 (pins 1, 2, and 7) 1/	-0.3 V dc to 7.0 V dc
Device types 02 and 03 (pins 8 and 9) 1/	-0.3 V dc to 6.0 V dc
Clock output current	-5.0 mA
Error amplifier output current	5.0 mA
Soft start sink current	20 mA
Oscillator charging current	-5.0 mA
Power dissipation (P_D) 2/ 3/	1.0 W
Storage temperature range	-65°C to +150°C
Lead temperature (soldering, 10 seconds)	+300°C
Junction temperature (T_J)	+150°C
Thermal resistance, junction-to-case (θ_{JC})	See MIL-STD-1835
Thermal resistance, junction-to-ambient (θ_{JA}) :	
Case outline E	80°C/W
Case outline 2	70°C/W
Power ground :	
Device types 02 and 03	± 0.2 V

1.4 Recommended operating conditions.

Supply voltage (V_S)	10 V dc to 30 V dc
Ambient operating temperature range (T_A)	-55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

- 1/ All references to pin numbers are for case outline E.
2/ For case E, derate linearly above $T_A = +60^\circ\text{C}$ at 11 mW/ $^\circ\text{C}$. For case 2, derate linearly above $T_A = +40^\circ\text{C}$ at 9 mW/ $^\circ\text{C}$.
3/ Must withstand the added P_D due to short circuit test; e.g., I_{SC} .

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 3

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

MIL-STD-883 - Test Method Standard Microcircuits.
MIL-STD-973 - Configuration Management.
MIL-STD-1835 - Interface Standard For Microcircuit Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

MIL-HDBK-103 - List of Standard Microcircuit Drawings (SMD's).
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device classes Q and V shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. The individual item requirements for device class M shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein for device classes Q and V or MIL-PRF-38535, appendix A and herein for device class M.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Block diagram(s). The block diagram(s) shall be as specified on figure 2.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table IIA. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device. For RHA product using this option, the RHA designator shall still be marked. Marking for device classes Q and V shall be in accordance with MIL-PRF-38535. Marking for device class M shall be in accordance with MIL-PRF-38535, appendix A.

3.5.1 Certification/compliance mark. The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-PRF-38535. The compliance mark for device class M shall be a "C" as required in MIL-PRF-38535, appendix A.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 4

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Reference section							
Output voltage	V _{REF}	T _J = +25°C, I _O = 1.0 mA	1	All	5.05	5.15	V
Line regulation	V _{RLN}	10 V < V _S < 30 V	1, 2, 3	01		±20	mV
		12 V < V _S < 20 V		02, 03		±15	
Load regulation	V _{RLD}	1.0 mA < I _O < 10 mA	1, 2, 3	All		±20	mV
Long term stability <u>3/</u>	$\frac{\Delta V_{REF}}{\Delta t}$	T _J = +125°C, t = 1000 hours	2	All		±25	mV
Output noise voltage <u>3/</u>	N _O	10 Hz < f < 10 kHz, T _A = +25°C	1	All		200	μV
Total output variation <u>3/</u>	V _{OM1}	I _O = -1.0 mA, V _S = 10 V	1, 2, 3	All	5.00	5.20	V
	V _{OM2}	I _O = -1.0 mA, V _S = 30 V			5.00	5.20	
	V _{OM3}	I _O = -10 mA, V _S = 10 V			5.00	5.20	
	V _{OM4}	I _O = -10 mA, V _S = 30 V			5.00	5.20	
Short circuit current	I _{SC}	V _{REF} = 0 V	1, 2, 3	01	-15	-100	mA
				02, 03	-30	-90	

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 5

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Oscillator section							
Initial accuracy	f _o	T _J = +25°C	4	01	360	440	kHz
				02, 03	375	425	
Voltage stability	$\frac{\Delta f_o}{\Delta V}$	10 V < V _S < 30 V	4, 5, 6	01		±2.0	%
		12 V < V _S < 20 V		02, 03		±1.0	
Total variation <u>3/</u>	f _{OM1}	V _S = 10 V	4, 5, 6	01	340	460	kHz
				02, 03	350	450	
	f _{OM2}	V _S = 30 V		01	340	460	
				02, 03	350	450	
Clock out high	V _{CKH}		1, 2, 3	01	3.9		V
				02, 03	3.7		
Clock out low	V _{CKL}		1, 2, 3	ALL		2.9	V
Ramp voltage, peak <u>3/</u>	V _{RP}		1, 2, 3	ALL	2.6	3.0	V
Ramp voltage, valley <u>3/</u>	V _{RV}		1, 2, 3	ALL	0.7	1.25	V

See footnotes at end of table.

**STANDARD
MICROCIRCUIT DRAWING**
DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

SIZE
A

REVISION LEVEL
C

5962-89905

SHEET
6

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions 1/ 2/ -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Oscillator section - continued							
Ramp voltage, valley to peak 3/	V _{RVP}		1, 2, 3	ALL	1.6	2.0	V
Oscillator discharge current	I _{OD}	R _T = open, V _(CT) = 2.0 V	1, 2, 3	02, 03	9.0	11.0	V
Error amplifier section							
Input offset voltage	V _{IO}	V _{CM} = 3.0 V, V _O = 3.0 V	1, 2, 3	ALL		±10	mV
Input bias current	I _{IS}	V _{CM} = 3.0 V, V _O = 3.0 V	1, 2, 3	ALL		3.0	μA
Input offset current	I _{IO}	V _{CM} = 3.0 V, V _O = 3.0 V	1, 2, 3	ALL		±1.0	μA
Open loop gain	A _{VOL}	1.0 V < V _O < 4.0 V	4, 5, 6	ALL	60		dB
Common mode rejection ratio	CMRR	1.5 V < V _{CM} < 5.5 V, V _{OUT} = 3.0 V	4, 5, 6	ALL	75		dB
Power supply rejection ratio	PSRR	10 V < V _S < 30 V, V _{OUT} = 3.0 V	4, 5, 6	01	85		dB
		12 V < V _S < 20 V, V _{OUT} = 3.0 V		02, 03	85		
Output sink current	I _{SNK}	V _{PIN3} = 1.0 V	1, 2, 3	ALL	1.0		mA
Output source current	I _{SRC}	V _{PIN3} = 4.0 V	1, 2, 3	ALL	-0.5		mA
Output high voltage	V _{OH1}	I _{PIN3} = -0.5 mA	1, 2, 3	01	4.0	5.0	V
				02, 03	4.5	5.0	

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 7

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Error amplifier section - continued							
Output low voltage	V _{OL1}	I _{PIN3} = 1.0 mA	1, 2, 3	ALL	0	1.0	V
Unity gain bandwidth <u>3/</u>	BW	f = 200 kHz	4, 5, 6	01	3.0		MHz
				02, 03	6.0		
Slew rate <u>3/</u>	SR		4, 5, 6	ALL	6.0		V/μs
PWM comparator section							
Pin 7 bias current	I _{BP7}	V _{PIN7} = 0 V	1, 2, 3	01		-5.0	μA
				02, 03		-8.0	
Duty cycle range	DC _{RG}		4, 5, 6	01	0	80	%
				02, 03	0	85	
Pin 3 zero dc threshold voltage	V _{TH}	V _{PIN7} = 0 V	1, 2, 3	ALL	1.1	1.4	V
Delay to output <u>3/</u>	t _{DI}		9, 10, 11	ALL		80	ns
Soft start duty cycle clamp section							
Charge current	I _{CHG}	V _{PIN8} = 0.5 V	1, 2, 3	01	3.0	20	μA
		V _{PIN8} = 2.5 V		02, 03	8.0	20	

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 8

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Soft start duty cycle clamp section - continued							
Discharge current	I _{DCG}	V _{PIN8} = 1.0 V	1, 2, 3	01	1.0		mA
		V _{PIN8} = 2.5 V		02, 03	100	350	μA
Current limit / shutdown section							
Pin 9 bias current	I _{BP9}	0 V < V _{PIN9} < 4.0 V	1, 2, 3	01		±10	μA
		0 V < V _{PIN9} < 2.0 V		02, 03		±15	
Current limit offset voltage	V _{LIM}	V _{PIN11} = 1.1 V	1, 2, 3	01		15	mV
Shutdown threshold	V _{SDN}		1, 2, 3	01	1.25	1.55	V
Current limit common mode range	I _{CMR}		1, 2, 3	01	1.0	1.25	V
Delay to output <u>3/</u>	t _{D2}		9, 10, 11	ALL		80	ns
Output section							
Output low level	V _{OL2}	I _{OUT} = 20 mA	1, 2, 3	ALL		0.4	V
		I _{OUT} = 200 mA				2.2	

See footnotes at end of table.

STANDARD
MICROCIRCUIT DRAWING
 DEFENSE SUPPLY CENTER COLUMBUS
 COLUMBUS, OHIO 43216-5000

SIZE
A

REVISION LEVEL
C

5962-89905

SHEET
9

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Output section - continued							
Output high level	V _{OH2}	I _{OUT} = -20 mA	1, 2, 3	01	13.0		V
				02, 03		2.9	
		I _{OUT} = -200 mA		01	12.0		
				02, 03		3.0	
Collector leakage	I _{LC}	V _C = 30 V	1, 2, 3	01		500	μA
		V _C = 20 V		02, 03		150	
Rise time <u>3/</u>	t _r	C _L = 1.0 nF	9, 10, 11	01		60	ns
				02, 03		45	
Fall time <u>3/</u>	t _f	C _L = 1.0 nF	9, 10, 11	01		60	ns
				02, 03		45	
UVLO output low saturation	V _{OLS}	I _O = 20 mA	1, 2, 3	02, 03		1.2	V
Under voltage lockout section							
Start threshold	V _{TH}		1, 2, 3	01	8.8	9.6	V
				02	8.4	9.6	
				03		17	

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 10

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Under voltage lockout section - continued							
Stop threshold	V _{STH}		1, 2, 3	03	9.0		V
UVLO hysteresis	V _{hys}		1, 2, 3	01, 02	0.4	1.2	V
				03	5.0	7.0	
Supply current							
Start-up current	I _{STR}	V _S = 8.0 V	1, 2, 3	01		2.5	mA
		V _C = V _{CC} = V _{TH(START)} − 0.5 V		02, 03		0.3	
Supply current	I _S	V _{PIN1,PIN7, and PIN9} = 0 V, V _{PIN2} = 1.0 V	1, 2, 3	01		33	mA
				02, 03		36	

1/ Unless specified otherwise, characteristics apply at R_T = 3.65 kΩ, C_T = 1.0 nF, V_S = 15 V.

2/ All references to pin numbers are for case outline E.

3/ Guaranteed, if not tested, to the specified limits in table I.

3.6 Certificate of compliance. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.6.1 herein). For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6.2 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and herein or for device class M, the requirements of MIL-PRF-38535, appendix A and herein.

3.7 Certificate of conformance. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 or for device class M in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DSCC-VA of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change as defined in MIL-STD-973.

3.9 Verification and review for device class M. For device class M, DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 Microcircuit group assignment for device class M. Device class M devices covered by this drawing shall be in microcircuit group number 110 (see MIL-PRF-38535, appendix A).

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 11

Device type	01, 02, 03	02, 03
Case outline	E	2
Terminal number	Terminal symbol	
1	INVERTING INPUT	N/C
2	NONINVERTING INPUT	INVERTING INPUT
3	ERROR AMPLIFIER OUTPUT	NONINVERTING INPUT
4	CLOCK	ERROR AMPLIFIER OUTPUT
5	R _T	CLOCK
6	C _T	N/C
7	RAMP	R _T
8	SOFT START	C _T
9	CURRENT LIMIT SHUT DOWN	RAMP
10	GROUND	SOFT START
11	CURRENT LIMIT REFERENCE	N/C
12	POWER GROUND	CURRENT LIMIT SHUT DOWN
13	V _C	GROUND
14	OUTPUT	OUTPUT A
15	V _S	POWER GROUND
16	VOLTAGE REFERENCE 5.1 VOLTS	N/C
17	----	V _C
18	----	OUTPUT B
19	----	V _S
20	----	VOLTAGE REFERENCE 5.1 VOLTS

FIGURE 1. Terminal connections.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 12

Device type 01

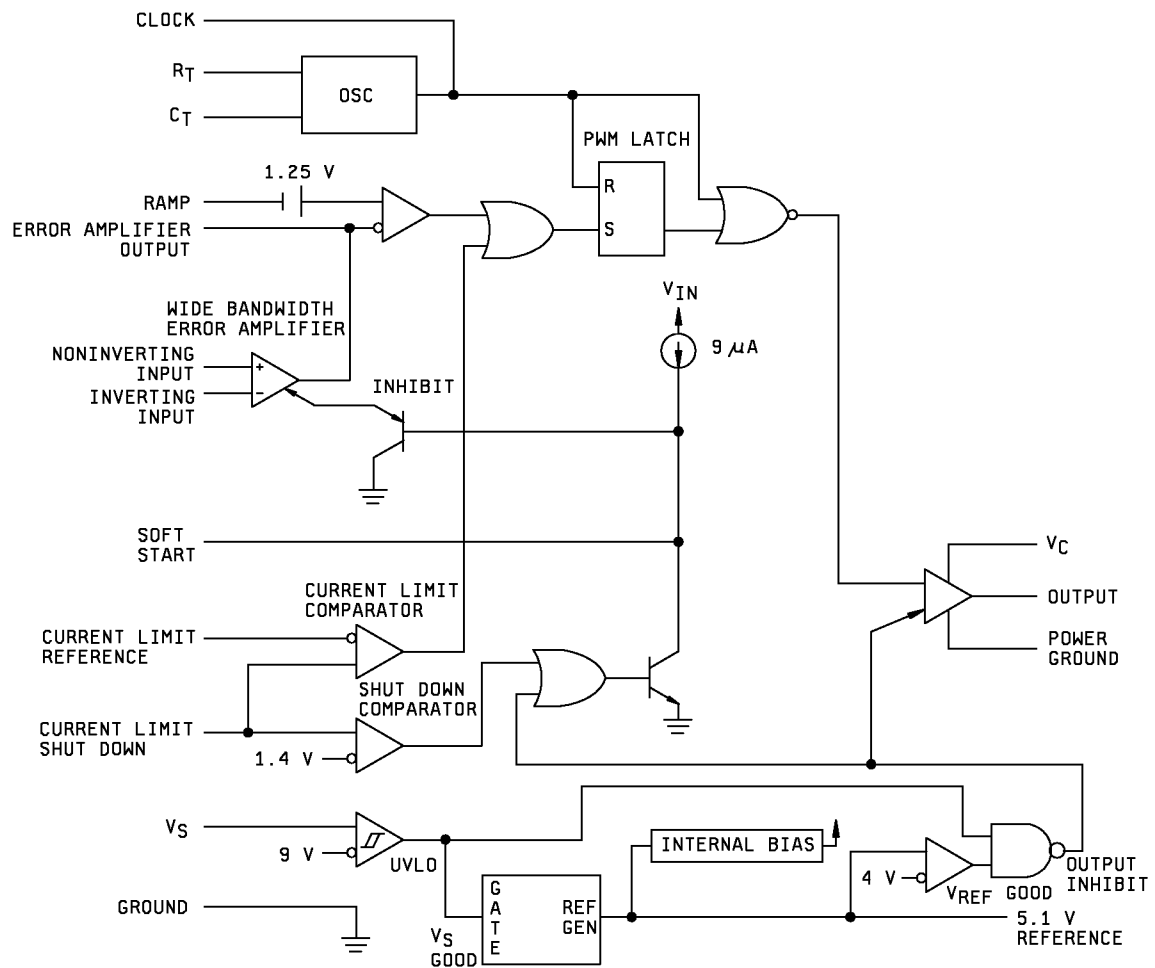
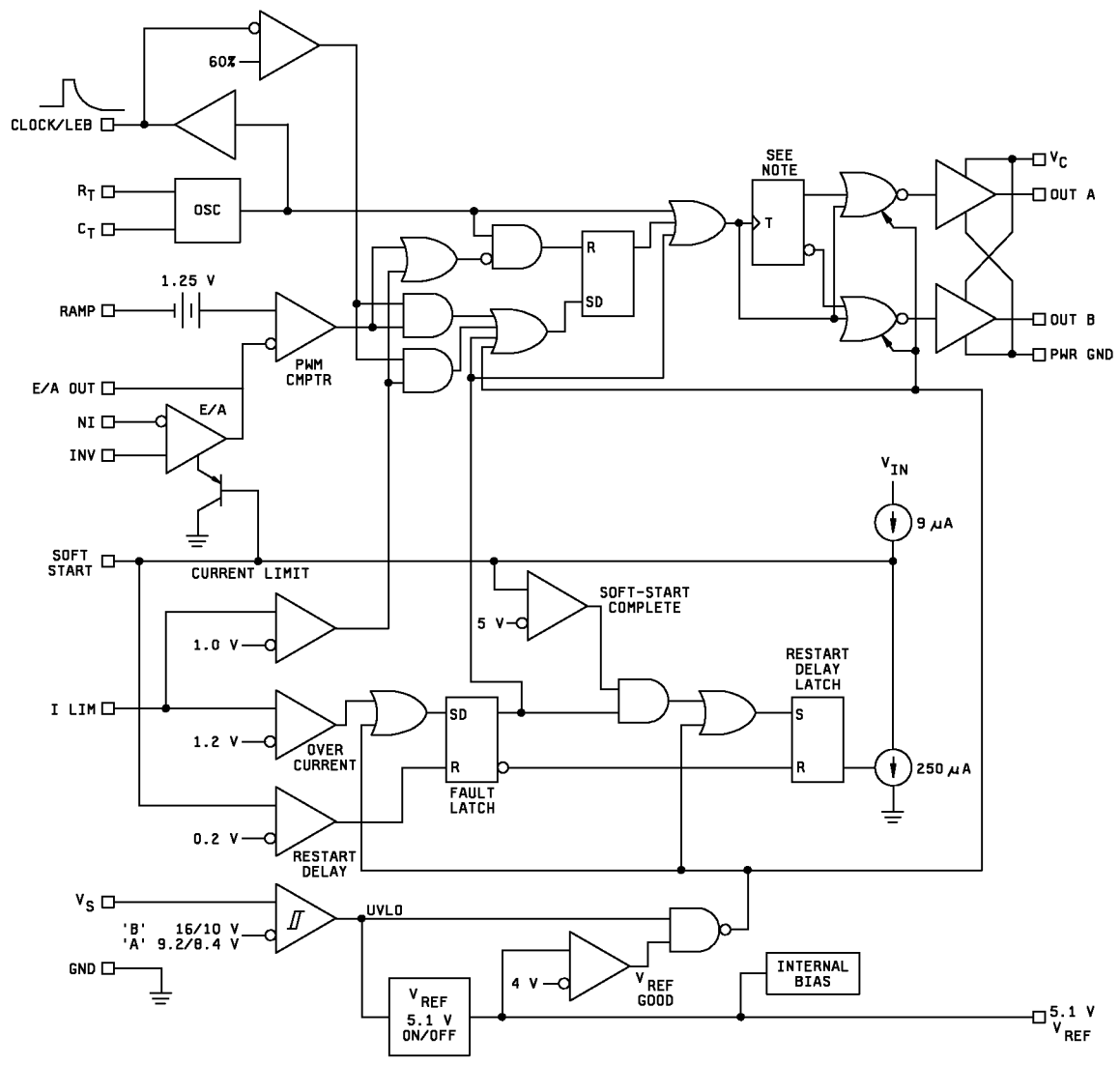


FIGURE 2. Block diagram.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 13

Device types 02 and 03



NOTE: Device 02 and 03 toggles Q and \bar{Q} are always low.

FIGURE 2. Block diagram - Continued.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 14

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. For device class M, sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection.

4.2.1 Additional criteria for device class M.

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015.

(2) $T_A = +125^{\circ}\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table IIA herein.

4.2.2 Additional criteria for device classes Q and V.

a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

b. Interim and final electrical test parameters shall be as specified in table IIA herein.

c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in MIL-PRF-38535, appendix B.

4.3 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-PRF-38535. Inspections to be performed shall be those specified in MIL-PRF-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4 Conformance inspection. Technology conformance inspection for classes Q and V shall be in accordance with MIL-PRF-38535 including groups A, B, C, D, and E inspections and as specified herein except where option 2 of MIL-PRF-38535 permits alternate in-line control testing. Quality conformance inspection for device class M shall be in accordance with MIL-PRF-38535, appendix A and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 15

TABLE IIA. Electrical test requirements.

Test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)	Subgroups (in accordance with MIL-PRF-38535, table III)	
	Device class M	Device class Q	Device class V
Interim electrical parameters (see 4.2)	1	1	1
Final electrical parameters (see 4.2)	1, 2, 3, 4 <u>1/</u>	1, 2, 3, 4 <u>1/</u>	1,2,3,4 <u>1/</u> <u>2/</u>
Group A test requirements (see 4.4)	1, 2, 3, 4, 5, 6, <u>3/</u> 9, 10, 11	1, 2, 3, 4, 5, 6, 9, 10, 11 <u>3/</u>	1, 2, 3, 4, 5, 6, 9, 10, 11 <u>3/</u>
Group C end-point electrical parameters (see 4.4)	1, 2, 3	1, 2, 3	1, 2, 3 <u>2/</u>
Group D end-point electrical parameters (see 4.4)	1, 2, 3	1, 2, 3	1, 2, 3
Group E end-point electrical parameters (see 4.4)	----	----	----

1/ PDA applies to subgroup 1.

2/ Delta limits in accordance with table IIB shall be computed with reference to the previous interim electrical parameters.

3/ Subgroups 9, 10, and 11, if not tested, shall be guaranteed to the limits specified in table I.

TABLE IIB. 240 hour burn-in and group C end-point electrical parameters.

Parameter	Delta	Unit
Output voltage	±0.025	V
Output low saturation voltage	±0.2	V
Output high saturation voltage	±0.2	V
Supply current	±10	mA

4.4.1 Group A inspection.

- a. Tests shall be as specified in table IIA herein.
- b. Subgroups 7 and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition A, B, C or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
- b. $T_A = +125^\circ\text{C}$, minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 16

4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.4 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein).

- a. End-point electrical parameters shall be as specified in table IIA herein.
- b. For device classes Q and V, the devices or test vehicle shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535 for the RHA level being tested. For device class M, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535, appendix A for the RHA level being tested. All device classes must meet the postirradiation end-point electrical parameter limits as defined in table I at $T_A = +25^{\circ}\text{C} \pm 5^{\circ}\text{C}$, after exposure, to the subgroups specified in table IIA herein.
- c. When specified in the purchase order or contract, a copy of the RHA delta limits shall be supplied.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-973 using DD Form 1692, Engineering Change Proposal.

6.3 Record of users. Military and industrial users should inform Defense Supply Center Columbus when a system application requires configuration control and which SMD's are applicable to that system. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0525.

6.4 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000, or telephone (614) 692-0674.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535 and MIL-HDBK-1331.

6.6 Sources of supply.

6.6.1 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DSCC-VA and have agreed to this drawing.

6.6.2 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-89905
		REVISION LEVEL C	SHEET 17

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 99-11-04

Approved sources of supply for SMD 5962-89905 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-8990501EA	48726	UC1823J/883BC
5962-89905012A	48726	UC1823L/883BC
5962-8990502VEA	48726	UC1823AJQMLV
5962-8990502EA	48726	UC1823AJ883B
5962-89905022A	48726	UC1823AL883B
5962-8990503EA	48726	UC1823BJ883B
5962-89905032A	48726	UC1823BL883

1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.

2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
number

48726

Vendor name
and address

Unitrode Integrated Circuits Division
7 Continental Boulevard
Merrimack, NH 03054

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.